

Notice of References Cited	Application/Control No. 10/708,365	Applicant(s)/Patent Under Reexamination HUNG ET AL.	
	Examiner Jeff Piziali	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0158862 A1	10-2002	Chen et al.	345/211
*	B	US-7,187,375 B2	03-2007	Ha et al.	345/212
*	C	US-6,987,499 B2	01-2006	Yamaguchi et al.	345/89
*	D	US-6,836,232 B2	12-2004	Bu, Lin-Kai	341/144
*	E	US-6,731,259 B2	05-2004	Yer et al.	345/89
*	F	US-6,680,733 B2	01-2004	Woo et al.	345/212
*	G	US-6,593,934 B1	07-2003	Liaw et al.	345/590
*	H	US-6,535,152 B2	03-2003	Lee, Bum-Ha	341/118
*	I	US-6,437,716 B2	08-2002	Nakao, Tomoaki	341/118
*	J	US-6,424,281 B1	07-2002	Liaw et al.	341/144
*	K	US-6,359,389 B1	03-2002	Medina et al.	315/169.1
*	L	US-6,297,790 B1	10-2001	Goode et al.	345/87
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.